

# 5SNA 1800G330400

## HiPak IGBT module



- $V_{CE} = 3300\text{ V}$
- $I_C = 1800\text{ A}$
- Ultra-low loss TSPT+ technology
- Very soft switching FCE diode with increased diode area
- Exceptional ruggedness and highest current rating
- High insulation package
- AlSiC base-plate for high power cycling capability
- AlN substrate for low thermal resistance
- Recognized under UL1557, File E 196689

Maximum rated values <sup>1)</sup>

Parameter	Symbol	Conditions	min	max	Unit
Collector-emitter voltage	$V_{CES}$	$V_{GE} = 0\text{ V}, T_{vj} \geq 25\text{ °C}$		3300	V
		$V_{GE} = 0\text{ V}, T_{vj} = -40\text{ °C}$		3000	
DC collector current	$I_C$	$T_C = 98\text{ °C}, T_{vj} = 150\text{ °C}$		1800	A
Peak collector current	$I_{CM}$	$t_p = 1\text{ ms}$		3600	A
Gate-emitter voltage	$V_{GES}$		-20	20	V
DC forward current	$I_F$			1800	A
Peak forward current	$I_{FRM}$	$t_p = 1\text{ ms}$		3600	A
Surge current	$I_{FSM}$	$V_R = 0\text{ V}, T_{vj\text{ start}} = 150\text{ °C},$ $t_p = 10\text{ ms}, \text{ half-sinewave}$		14300	A
IGBT short circuit SOA	$t_{psc}$	$V_{CC} = 2500\text{ V}, V_{CEM\text{ CHIP}} \leq 3300\text{ V}$ $V_{GE} \leq 15\text{ V}, T_{vj\text{ start}} \leq 150\text{ °C}$		10	$\mu\text{s}$
Isolation voltage	$V_{ISOL}$	1 min, $f = 50\text{ Hz}$		10200	V
Junction temperature	$T_{vj}$			175	$^{\circ}\text{C}$
Junction operating temperature	$T_{vj(\text{op})}$		-40	150	$^{\circ}\text{C}$
Case temperature	$T_C$		-40	125	$^{\circ}\text{C}$
Storage temperature	$T_{stg}$		-50	125	$^{\circ}\text{C}$
Mounting torques <sup>2)</sup>	$M_s$	Base-heatsink, M6 screws	4	6	Nm
	$M_{t1}$	Main terminals, M8 screws	8	10	
	$M_{t2}$	Auxiliary terminals, M4 screws	2	3	

<sup>1)</sup> Maximum rated values indicate limits beyond which damage to the device may occur per IEC 60747

<sup>2)</sup> For detailed mounting instructions refer to ABB Document No. 5SYA 2039

IGBT characteristic values <sup>3)</sup>

Parameter	Symbol	Conditions	min	typ	max	Unit	
Collector (-emitter) breakdown voltage	$V_{(BR)CES}$	$V_{GE} = 0\text{ V}$ , $I_C = 10\text{ mA}$	$T_{vj} = 150\text{ °C}$	3300		V	
			$T_{vj} = 25\text{ °C}$	3300			
			$T_{vj} = -40\text{ °C}$	3000			
Collector-emitter <sup>4)</sup> saturation voltage	$V_{CEsat}$	$I_C = 1800\text{ A}$ , $V_{GE} = 15\text{ V}$	$T_{vj} = 25\text{ °C}$		2.3	2.7	V
			$T_{vj} = 125\text{ °C}$		2.75	3.2	
			$T_{vj} = 150\text{ °C}$		2.9		
Collector cut-off current	$I_{CES}$	$V_{CE} = 3300\text{ V}$ , $V_{GE} = 0\text{ V}$	$T_{vj} = 25\text{ °C}$			1	mA
			$T_{vj} = 125\text{ °C}$		22		
			$T_{vj} = 150\text{ °C}$		120		
Gate leakage current	$I_{GES}$	$V_{CE} = 0\text{ V}$ , $V_{GE} = \pm 20\text{ V}$ , $T_{vj} = 125\text{ °C}$	-500		500	nA	
Gate-emitter threshold voltage	$V_{GE(TO)}$	$I_C = 240\text{ mA}$ , $V_{CE} = V_{GE}$ , $T_{vj} = 25\text{ °C}$	6.7		8.7	V	
Gate charge	$Q_{ge}$	$I_C = 1800\text{ A}$ , $V_{CE} = 1800\text{ V}$ , $V_{GE} = -15\text{ V} \dots 15\text{ V}$		18		$\mu\text{C}$	
Input capacitance	$C_{ies}$	$V_{CE} = 25\text{ V}$ , $V_{GE} = 0\text{ V}$ , $f = 1\text{ MHz}$ , $T_{vj} = 25\text{ °C}$		239		nF	
Internal gate resistance	$R_{Gint}$			0.83		$\Omega$	
Turn-on delay time	$t_{d(on)}$	$V_{CC} = 1800\text{ V}$ , $I_C = 1800\text{ A}$ , $R_G = 1.2\ \Omega$ , $C_{GE} = 330\text{ nF}$ , $V_{GE} = \pm 15\text{ V}$ , $L_\sigma = 100\text{ nH}$ , inductive load	$T_{vj} = 25\text{ °C}$		1030	ns	
			$T_{vj} = 150\text{ °C}$		1035		
Rise time	$t_r$		$T_{vj} = 25\text{ °C}$		320	ns	
			$T_{vj} = 150\text{ °C}$		340		
Turn-off delay time	$t_{d(off)}$	$V_{CC} = 1800\text{ V}$ , $I_C = 1800\text{ A}$ , $R_G = 4.7\ \Omega$ , $C_{GE} = 330\text{ nF}$ , $V_{GE} = \pm 15\text{ V}$ , $L_\sigma = 100\text{ nH}$ , inductive load	$T_{vj} = 25\text{ °C}$		2930	ns	
			$T_{vj} = 150\text{ °C}$		3500		
Fall time	$t_f$		$T_{vj} = 25\text{ °C}$		390	ns	
			$T_{vj} = 150\text{ °C}$		490		
Turn-on switching energy	$E_{on}$	$V_{CC} = 1800\text{ V}$ , $I_C = 1800\text{ A}$ , $R_G = 1.2\ \Omega$ , $C_{GE} = 330\text{ nF}$ , $V_{GE} = \pm 15\text{ V}$ , $L_\sigma = 100\text{ nH}$ , inductive load	$T_{vj} = 25\text{ °C}$		3.35	J	
			$T_{vj} = 125\text{ °C}$		4.00		
			$T_{vj} = 150\text{ °C}$		4.55		
Turn-off switching energy	$E_{off}$	$V_{CC} = 1800\text{ V}$ , $I_C = 1800\text{ A}$ , $R_G = 4.7\ \Omega$ , $C_{GE} = 330\text{ nF}$ , $V_{GE} = \pm 15\text{ V}$ , $L_\sigma = 100\text{ nH}$ , inductive load	$T_{vj} = 25\text{ °C}$		3.00	J	
			$T_{vj} = 125\text{ °C}$		4.05		
			$T_{vj} = 150\text{ °C}$		4.35		
Short circuit current	$I_{sc}$	$V_{CC} = 2500\text{ V}$ , $V_{GE} = 15\text{ V}$	$T_{vj\text{ start}} = 150\text{ °C}$		6600	A	

<sup>3)</sup> Characteristic values according to IEC 60747 – 9<sup>4)</sup> Collector-emitter saturation voltage is given at chip level

Diode characteristic values <sup>5)</sup>

Parameter	Symbol	Conditions	min	typ	max	Unit	
Forward voltage <sup>6)</sup>	V <sub>F</sub>	I <sub>F</sub> = 1800 A	T <sub>vj</sub> = 25 °C	2.0	2.45	V	
			T <sub>vj</sub> = 125 °C		2.2		2.65
			T <sub>vj</sub> = 150 °C		2.15		
Peak reverse recovery current	I <sub>RM</sub>		T <sub>vj</sub> = 25 °C	1940		A	
			T <sub>vj</sub> = 125 °C		2230		
			T <sub>vj</sub> = 150 °C		2300		
Recovered charge	Q <sub>rr</sub>	V <sub>CC</sub> = 1800 V, I <sub>F</sub> = 1800 A, V <sub>GE</sub> = ±15 V, R <sub>G</sub> = 1.2 Ω, C <sub>GE</sub> = 330 nF, di/dt = 5.0 kA/μs, L <sub>σ</sub> = 100 nH, inductive load	T <sub>vj</sub> = 25 °C	1110		μC	
			T <sub>vj</sub> = 125 °C		1740		
			T <sub>vj</sub> = 150 °C		1920		
Reverse recovery time	t <sub>rr</sub>		T <sub>vj</sub> = 25 °C	1000		ns	
			T <sub>vj</sub> = 125 °C		1260		
			T <sub>vj</sub> = 150 °C		1380		
Reverse recovery energy	E <sub>rec</sub>		T <sub>vj</sub> = 25 °C	1.25		J	
			T <sub>vj</sub> = 125 °C		2.00		
			T <sub>vj</sub> = 150 °C		2.25		

<sup>5)</sup> Characteristic values according to IEC 60747 – 2

<sup>6)</sup> Forward voltage is given at chip level

Package properties <sup>7)</sup>

Parameter	Symbol	Conditions	min	typ	max	Unit	
IGBT thermal resistance junction to case	R <sub>th(j-c)IGBT</sub>				0.009	K/W	
Diode thermal resistance junction to case	R <sub>th(j-c)DIODE</sub>				0.014	K/W	
IGBT thermal resistance <sup>2)</sup> case to heatsink	R <sub>th(c-s)IGBT</sub>	IGBT per switch, λ grease = 1W/m x K		0.007		K/W	
Diode thermal resistance <sup>2)</sup> case to heatsink	R <sub>th(c-s)DIODE</sub>	Diode per switch, λ grease = 1W/m x K		0.010		K/W	
Partial discharge extinction voltage	V <sub>e</sub>	f = 50 Hz, Q <sub>PD</sub> ≤ 10 pC (acc. To IEC 61287)	5100			V	
Comparative tracking index	CTI		600				
Module stray inductance	L <sub>σ CE</sub>			18		nH	
Resistance, terminal-chip	R <sub>CC+EE'</sub>		T <sub>C</sub> = 25 °C	0.07		mΩ	
			T <sub>C</sub> = 125 °C		0.10		
			T <sub>C</sub> = 150 °C		0.11		

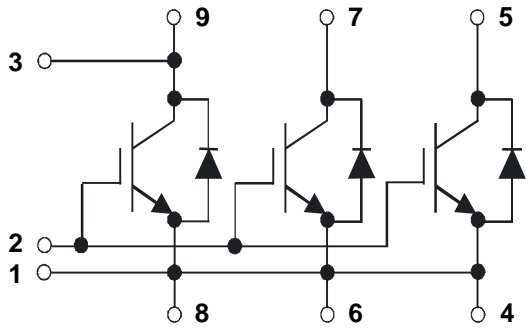
<sup>2)</sup> For detailed mounting instructions refer to ABB Document No. 5SYA 2039

Mechanical properties <sup>7)</sup>

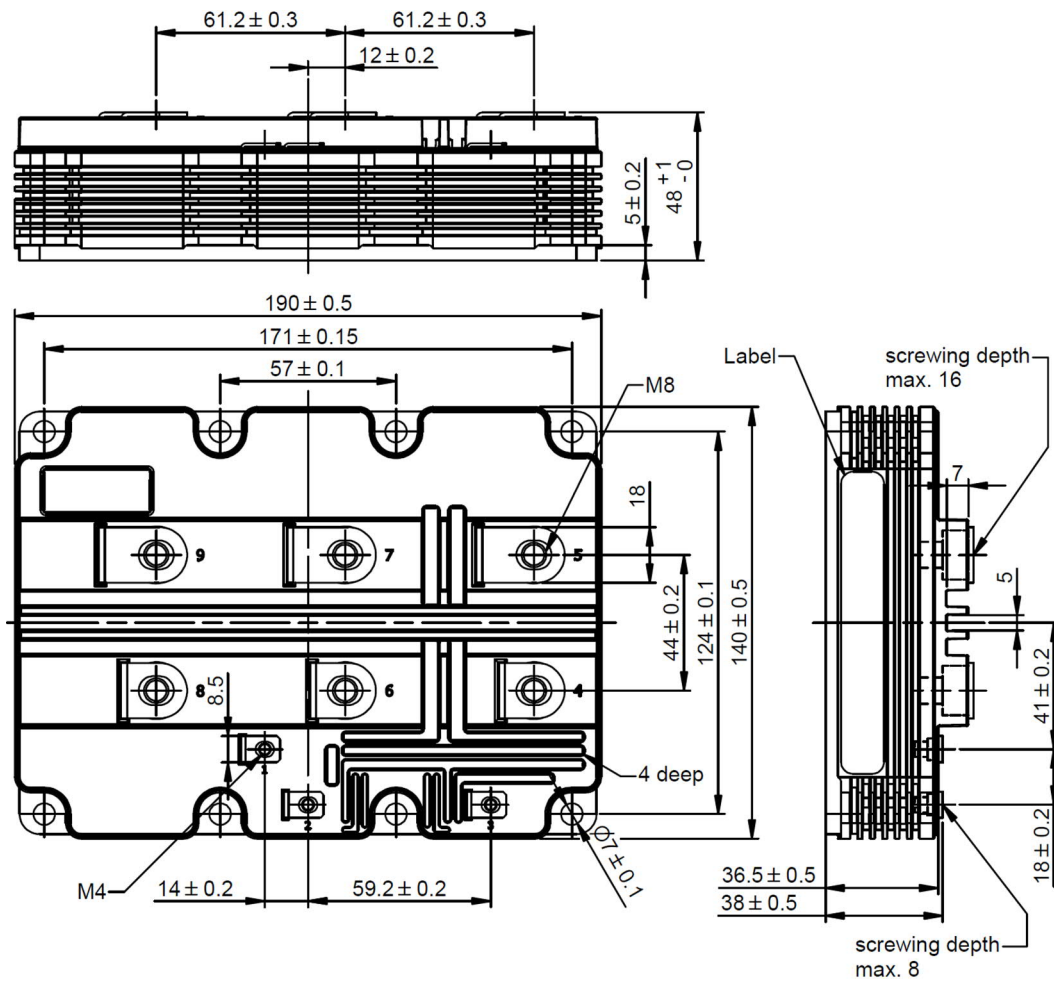
Parameter	Symbol	Conditions	min	typ	max	Unit
Dimensions	L x W x H	Typical		190 x 140 x 48		mm
Clearance distance in air	d <sub>a</sub>	according to IEC 60664-1 and EN 50124-1	Term. to base:	40		mm
			Term. to term:	26		
Surface creepage distance	d <sub>s</sub>	according to IEC 60664-1 and EN 50124-1	Term. to base:	64		mm
			Term. to term:	56		
Mass	m			1330		g

<sup>7)</sup> Package and mechanical properties according to IEC 60747 – 15

## Electrical configuration



## Outline drawing (mm)



Note: This is an electrostatic sensitive device, please observe the international standard IEC 60747-1, chap. VIII. This product has been designed and qualified for Industrial Level.

Fig. 1 Typical on-state characteristics, chip level

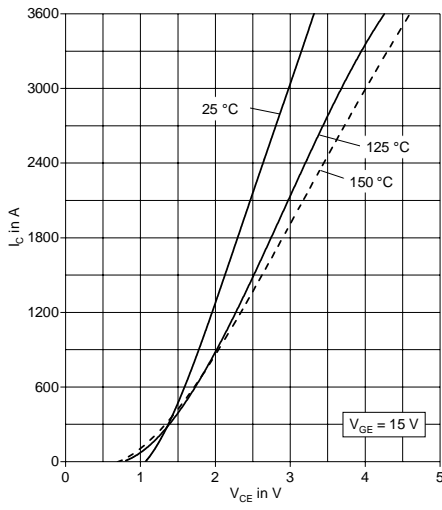


Fig. 2 Typical transfer characteristics, chip level

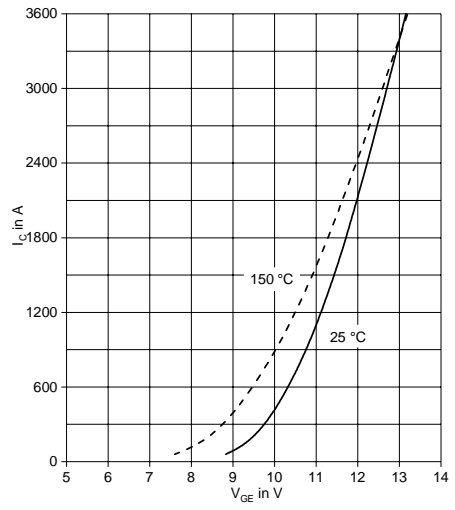


Fig. 3 Typical output characteristics, chip level

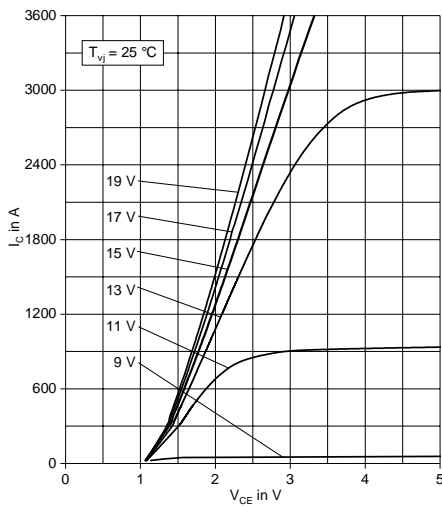


Fig. 4 Typical output characteristics, chip level

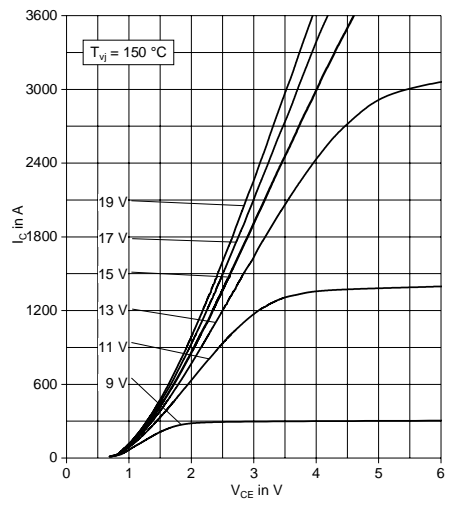


Fig. 5 Typical switching energies per pulse vs. collector current

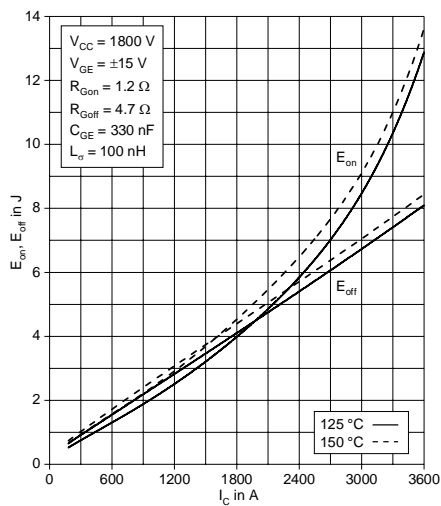


Fig. 6 Typical switching energies per pulse vs. gate resistor

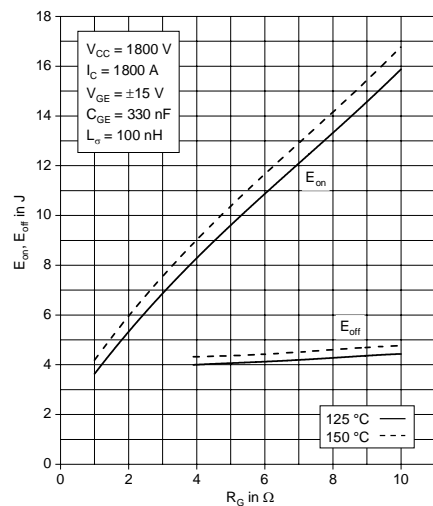


Fig. 7 Typical switching times vs. collector current

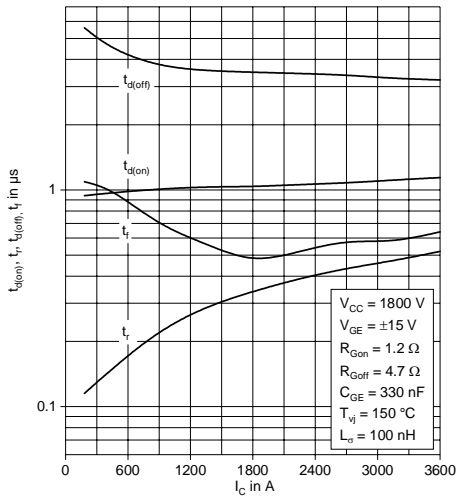


Fig. 8 Typical switching times vs. gate resistor

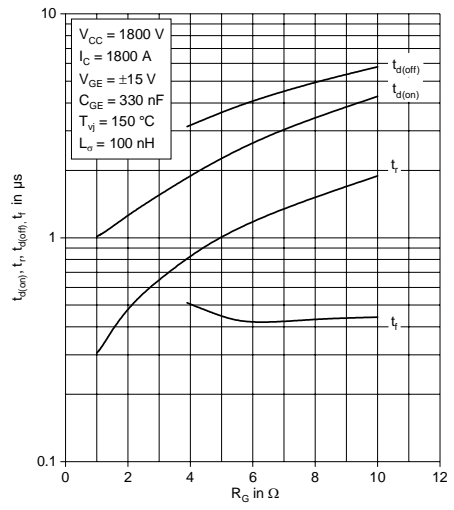


Fig. 9 Typical gate charge characteristics

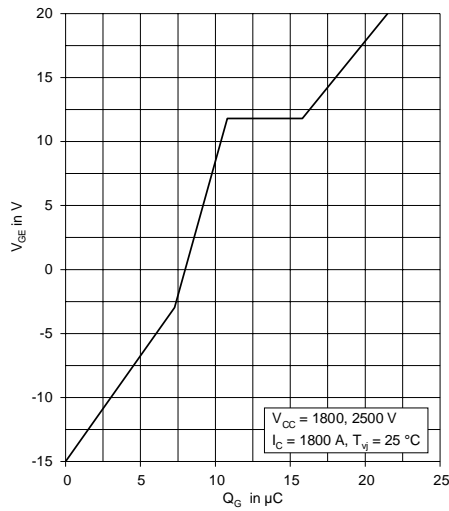


Fig. 10 Turn-off safe operating area (RBSOA)

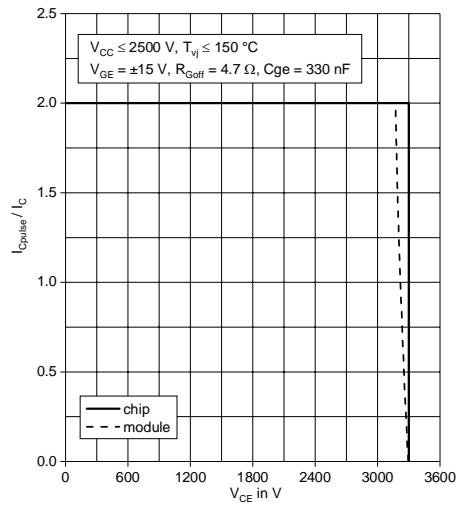


Fig. 11 Typical diode forward characteristics chip level

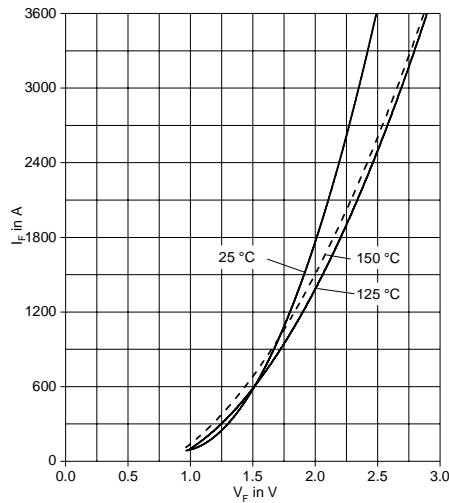


Fig. 12 Typical reverse recovery characteristics vs. forward current

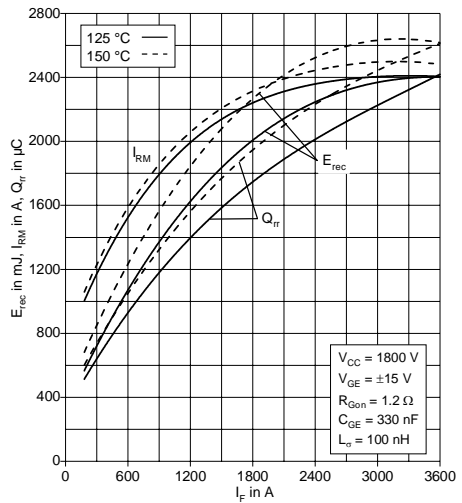


Fig. 13 Typical reverse recovery characteristics vs. di/dt

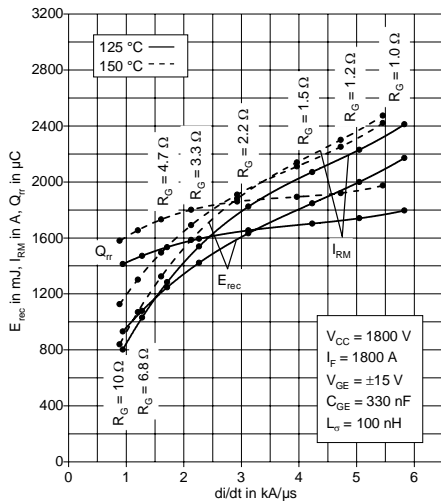


Fig. 14 Safe operating area diode (SOA)

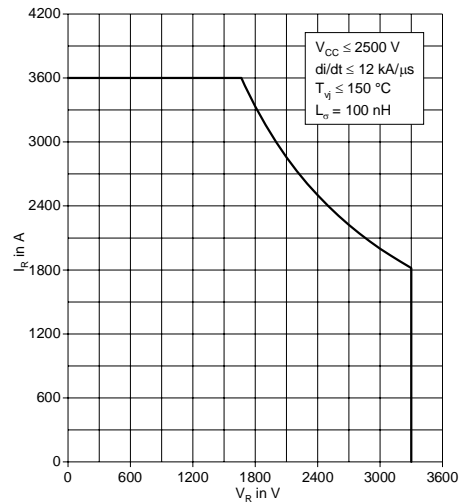
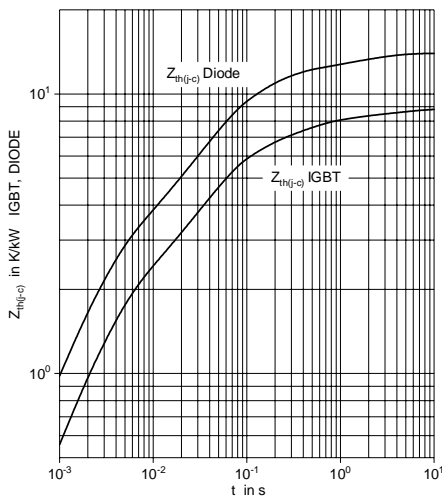


Fig. 15 Thermal impedance vs. time



Analytical function of the transient thermal resistance

$$Z_{th(j-c)}(t) = \sum_{i=1}^n R_i(1 - e^{-t/\tau_i})$$

	i	1	2	3	4	5
IGBT	Ri(K/kW)	1.631	4.286	2.089	0.855	
	$\tau_i$ (ms)	2.986	48.79	364.8	3593	
DIODE	Ri(K/kW)	2.441	4.230	5.055	2.253	
	$\tau_i$ (ms)	2.434	36.51	116.2	1641	

Related documents:

- 5SYA 2039 Mounting Instructions for HiPak modules
- 5SYA 2042 Failure rates of IGBT modules due to cosmic rays
- 5SYA 2043 Load – cycle capability of HiPaks
- 5SYA 2045 Thermal runaway during blocking
- 5SYA 2053 Applying IGBT
- 5SYA 2057 IGBT diode safe operating area (SOA)
- 5SYA 2058 Surge currents for IGBT diodes
- 5SYA 2093 Thermal design of IGBT modules
- 5SYA 2098 Paralleling of IGBT modules